Nov 2009

HD60N08 / HU60N08

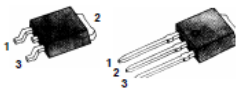
80V N-Channel MOSFET

BV_{DSS} = 80V

$R_{DS(on)}$ = 13 mΩ

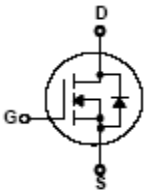
I_D = 60 A

TO-252 **TO-251**



HD60N75 **HU60N75**

1.Gate 2. Drain 3. Source



FEATURES

- Originative New Design
- Superior Avalanche Rugged Technology
- Robust Gate Oxide Technology
- Very Low Intrinsic Capacitances
- Excellent Switching Characteristics
- Unrivalled Gate Charge : 40 nC (Typ.)
- Extended Safe Operating Area
- Lower $R_{DS(ON)}$: 0.013 Ω (Typ.) @V_{GS}=10V
- 100% Avalanche Tested

Absolute Maximum Ratings

T_C=25℃ unless otherwise specified

Symbol	Parameter		Value	Units
V_{DSS}	Drain-Source Voltage		80	V
I_D	Drain Current – Continuous (T_C = 25℃)		60	A
	Drain Current – Continuous (T_C = 100℃)		41	A
I_{DM}	Drain Current – Pulsed	(Note 1)	100	A
V_{GS}	Gate-Source Voltage		±20	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	290	mJ
I_{AR}	Avalanche Current	(Note 1)	60	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	12	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P_D	Power Dissipation (T_A = 25℃)*		3.75	W
	Power Dissipation (T_C = 25℃)		85	W
	- Derate above 25℃		0.8	W/℃
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	℃
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	℃

Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	1.0	℃/W
$R_{\theta JA}$	Junction-to-Ambient*	--	40	
$R_{\theta JA}$	Junction-to-Ambient	--	62.5	

* When mounted on the minimum pad size recommended (PCB Mount)

80V_{DS}／±25V_{GS}／80A(I_D) N-Channel Enhancement Mode MOSFET

N-Channel Enhancement Mode MOSFET2

Electrical Characteristics (T_C=25℃unless otherwise noted)

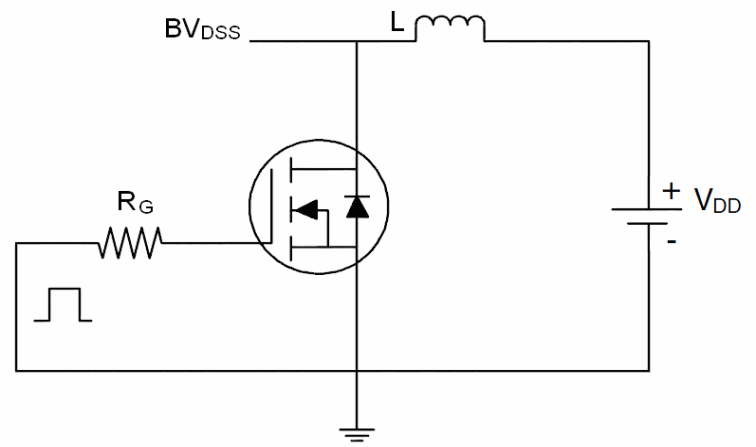
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	V_{GS}=0V I_D=250μA	80	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS}=80V,V_{GS}=0V	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	V_{GS}=±20V,V_{DS}=0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS}=V_{GS},I_D=250μA	2	3	4	V
Drain-Source On-State Resistance	$R_{DS(ON)}$	V_{GS}=10V, I_D=40A	-	13	16	mΩ
Forward Transconductance	g_{FS}	V_{DS}=5V,I_D=40A	30	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C_{lss}	V_{DS}=25V,V_{GS}=0V, F=1.0MHz	-	2498	-	PF
Output Capacitance	C_{oss}		-	185	-	PF
Reverse Transfer Capacitance	C_{rss}		-	80	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	$t_{d(on)}$	V_{DD}=30V,I_D=2A,R_L=1Ω V_{GS}=10V,R_{GEN}=3Ω	-	12	-	nS
Turn-on Rise Time	t_r		-	5.2	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	38	-	nS
Turn-Off Fall Time	t_f		-	27	-	nS
Total Gate Charge	Q_g	V_{DS}=30V,I_D=40A, V_{GS}=10V	-	36	-	nC
Gate-Source Charge	Q_{gs}		-	9.9	-	nC
Gate-Drain Charge	Q_{gd}		-	6.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V_{SD}	V_{GS}=0V,I_S=40A	-	-	1.2	V
Diode Forward Current (Note 2)	I_S		-	-	90	A
Reverse Recovery Time	t_{rr}	TJ = 25°C, IF =40A di/dt = 100A/μs (Note3)	-	35		nS
Reverse Recovery Charge	Qrr		-	47		nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

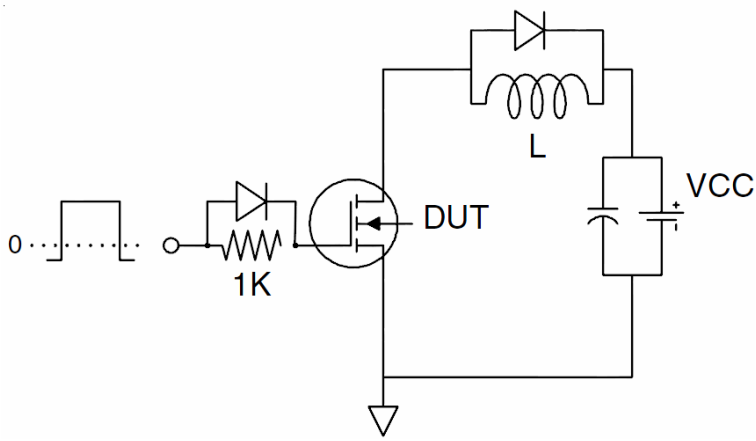
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, t ≤ 10 sec.
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: Tj=25℃,V_{DD}=30V,V_G=10V,L=0.5mH,Rg=25Ω

Test circuit

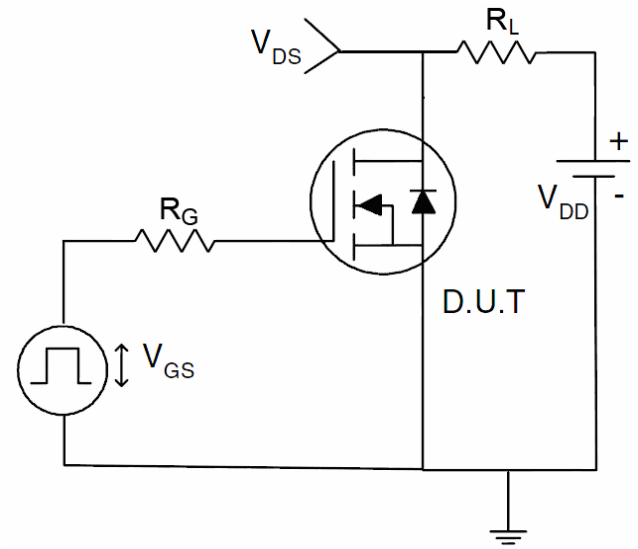
1) E_{AS} test Circuits



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

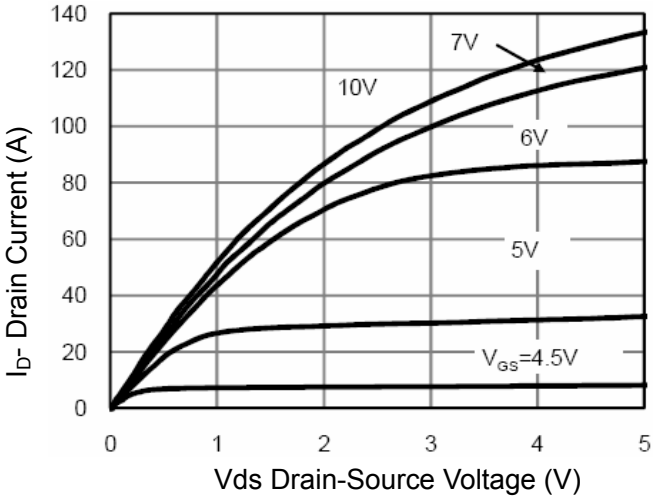


Figure 1 Output Characteristics

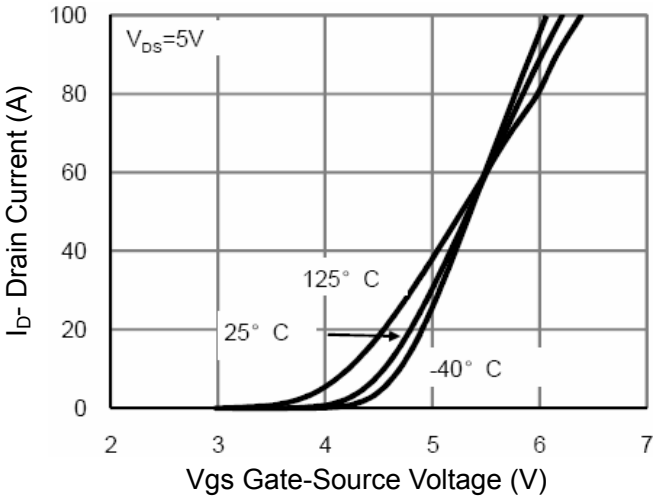


Figure 2 Transfer Characteristics

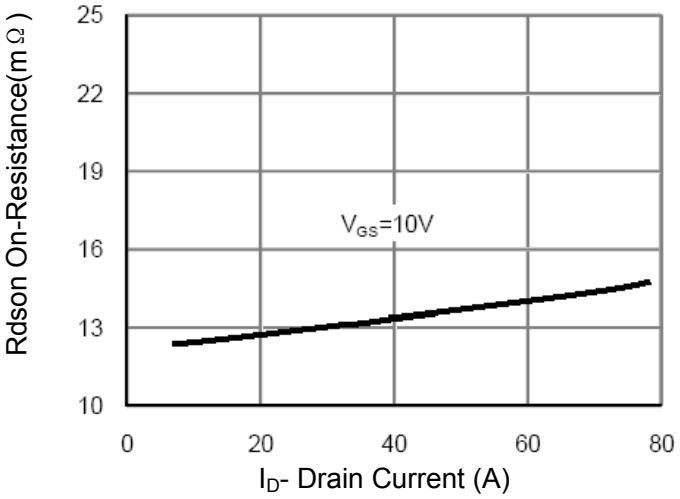


Figure 3 Rdson- Drain Current

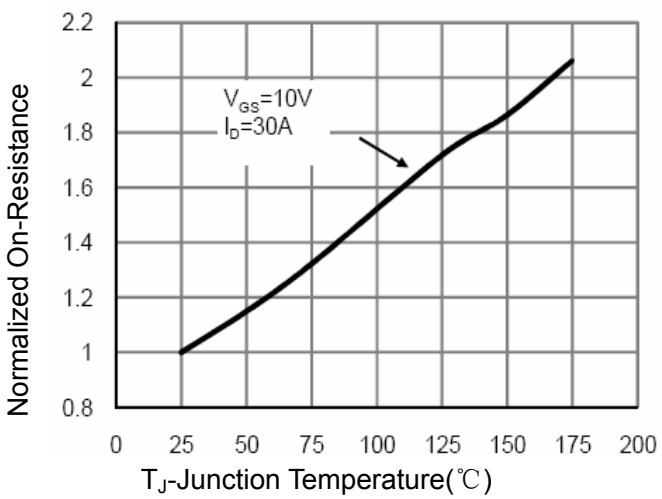


Figure 4 Rdson-JunctionTemperature

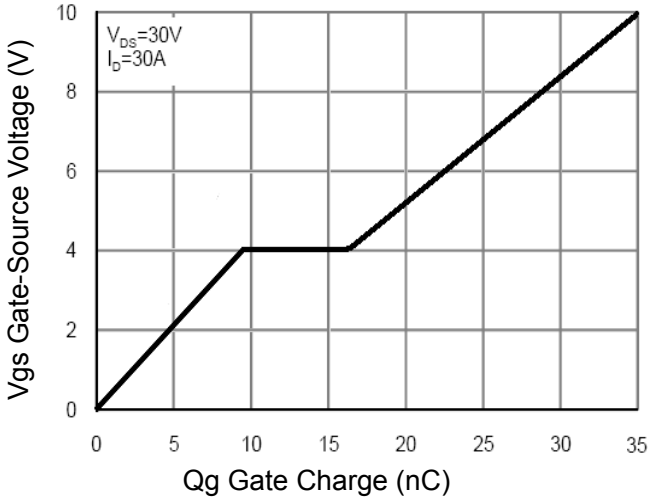


Figure 5 Gate Charge

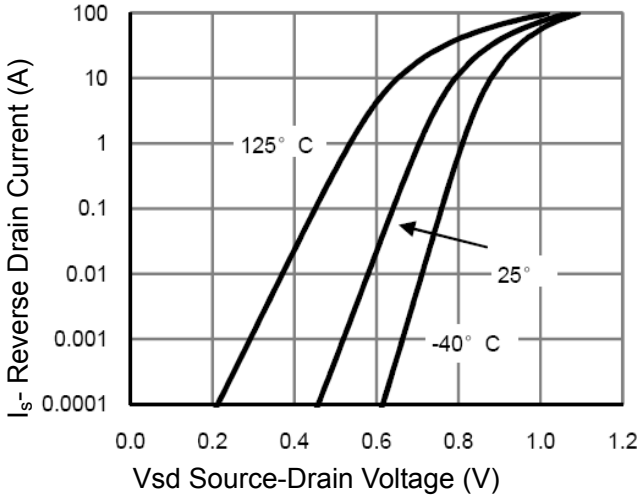


Figure 6 Source- Drain Diode Forward

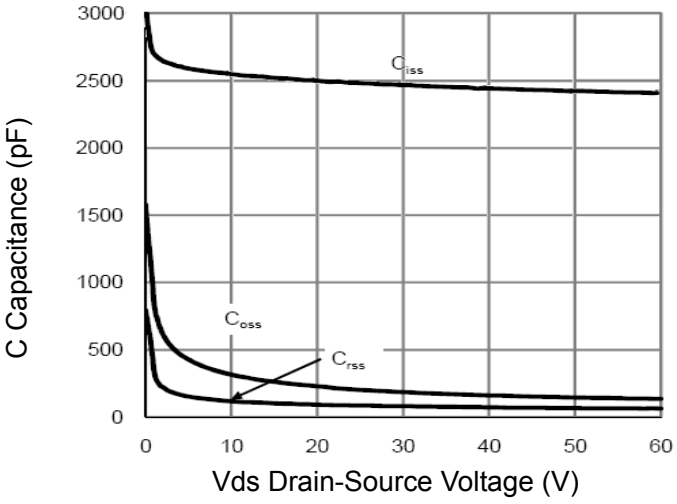


Figure 7 Capacitance vs Vds

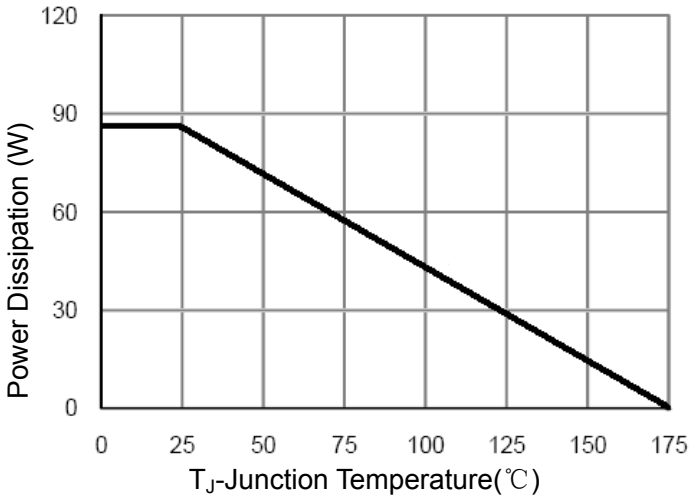


Figure 9 Power De-rating

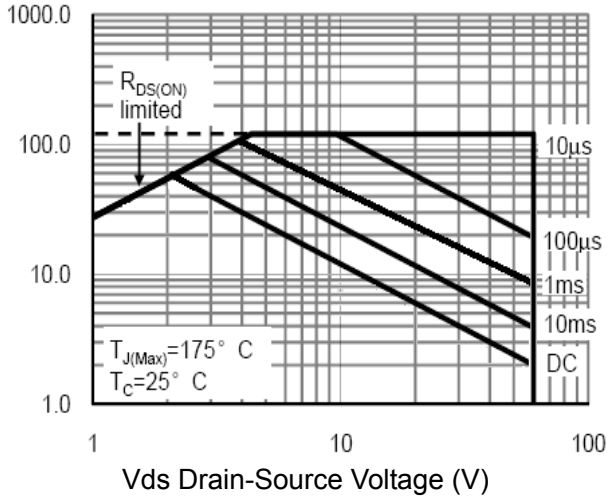


Figure 8 Safe Operation Area

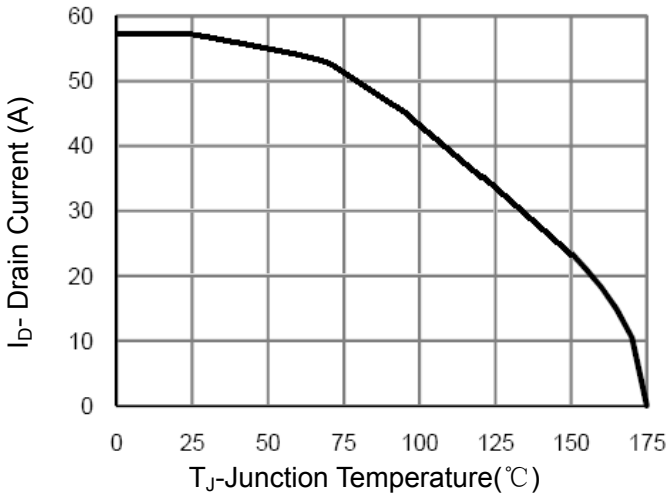


Figure 10 ID Current- JunctionTemperature

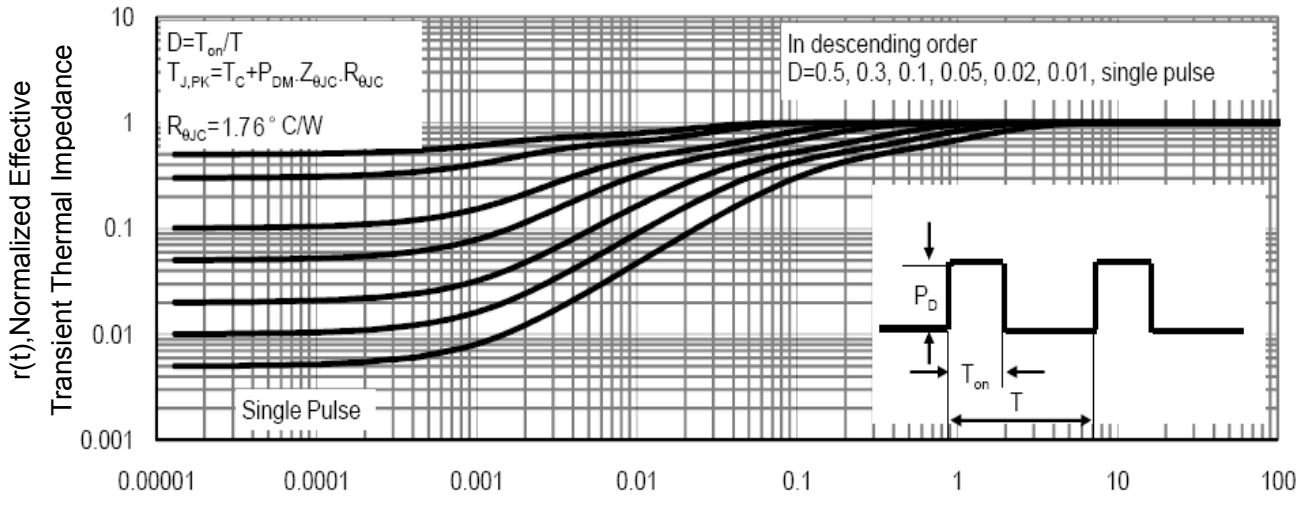
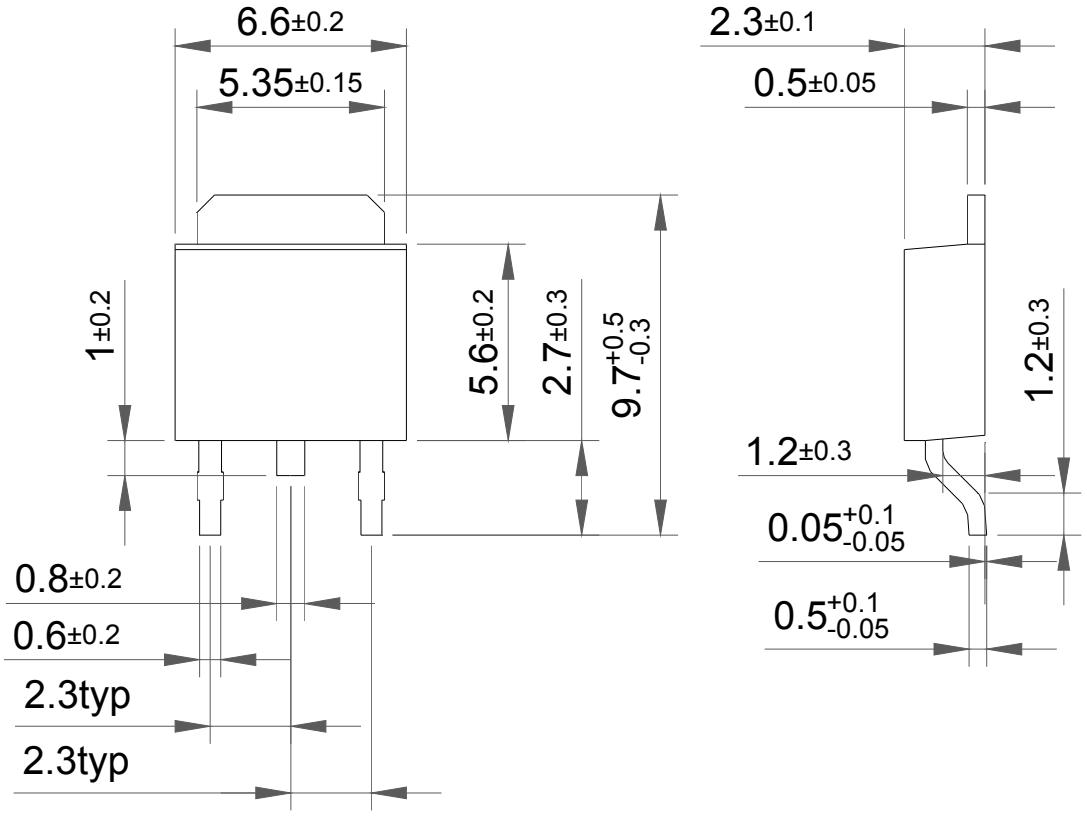


Figure 11 Normalized Maximum Transient Thermal Impedance

Package Dimension

TO-252



Package Dimension

TO-251